SDLS010

SN54LS114A, SN54S114, SN74LS114A, SN74S114A
DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET, COMMON CLEAR, AND COMMON CLOCK

MARCH 1973—REVISED MARCH 1988

- **Fully Buffered to Offer Maximum Isolation from External Disturbance**
- **Package Options Include Ceramic Carriers and Flat Packages in Addition to Plastic and Ceramic DIPs**
- **Dependable Texas Instruments Quality and Reliability**

description

These devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset and clear inputs sets or resets the outputs regardless of the levels of the other inputs. When preset and clear are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by tying J and K high.

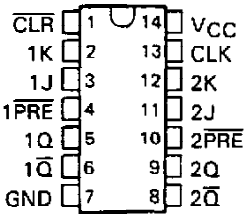
The SN54LS114A and SN54S114 are characterized for operation over the full military temperature range of −55°C to 125°C. The SN74LS114A and SN74S114A are characterized for operation from 0°C to 70°C.

FUNCTION TABLE

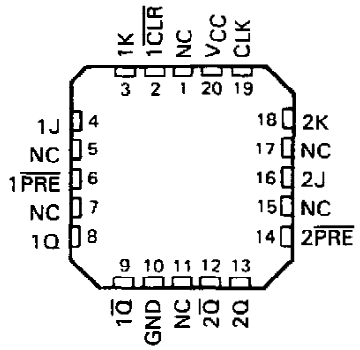
INPUTS					OUTPUTS	
$\overline{PRE}$	$\overline{CLR}$	CLK	J	K	Q	$\overline{Q}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H†	H†
H	H	↓	L	L	Q_0	$\overline{Q}_0$
H	H	↓	H	L	H	L
H	H	↓	L	H	L	H
H	H	↓	H	H	TOGGLE	
H	H	H	X	X	Q_0	$\overline{Q}_0$

† The output levels in this configuration are not guaranteed to meet the minimum levels for V_{OH} if the lows at preset and clear are near V_{IL} minimum. Furthermore, this configuration is nonstable; that is, it will not persist when either preset or clear returns to its inactive (high) level.

SN54LS114A, SN54S114 . . . J OR W PACKAGE
SN74LS114A, SN74S114A . . . D OR N PACKAGE
(TOP VIEW)

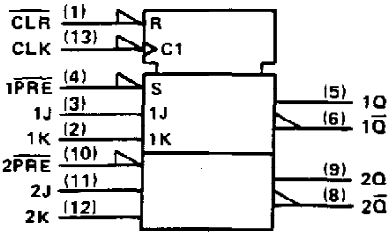


SN54LS114A, SN54S114 . . . FK PACKAGE
(TOP VIEW)



NC—No internal connection

logic symbol‡



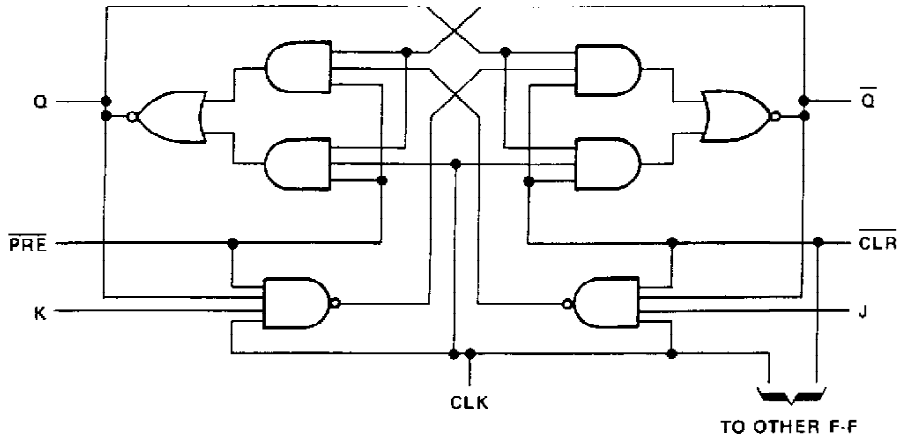
‡This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

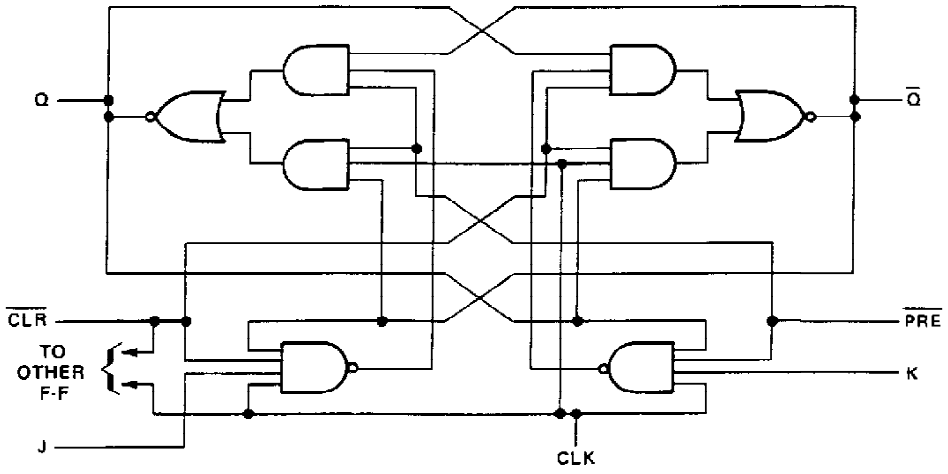
TEXAS INSTRUMENTS
POST OFFICE BOX 655012 • DALLAS, TEXAS 75265

logic diagram (positive logic)

'LS114A

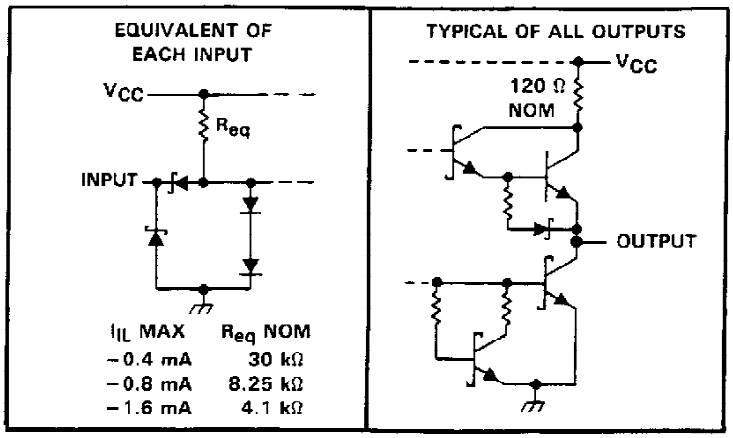


SN54S114, SN74S114A

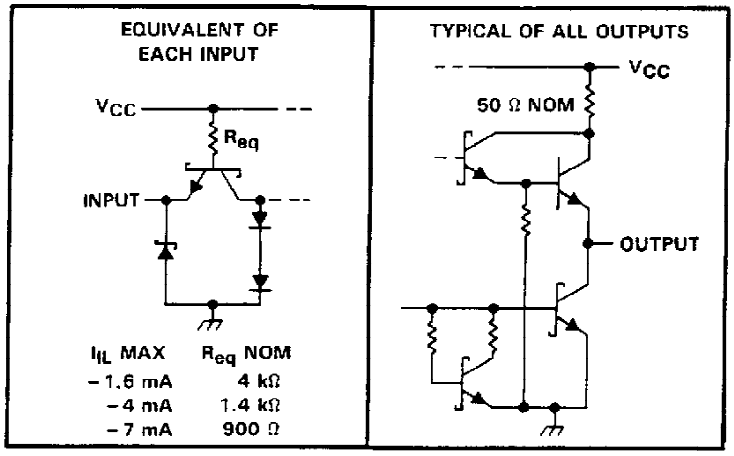


schematics of inputs and outputs

'LS114A



SN54S114, SN74S114A



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage: 'LS114A . . . . . 7 V
SN54S114, SN74S114A . . . . . 5.5 V
Operating free-air temperature range: SN54' . . . . . −55°C to 125°C
SN74' . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

			SN54LS114A			SN74LS114A			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.7			0.8	V
I_{OH}	High-level output current				−0.4			−0.4	mA
I_{OL}	Low-level output current				4			8	mA
f_{clock}	Clock frequency		0		30	0		30	MHz
t_w	Pulse duration	CLK	20			20			ns
		$\overline{PRE}$ or $\overline{CLR}$ low	25			25			
t_{su}	Set up time-before CLK↓	Data high or low	20			20			ns
		$\overline{CLR}$ inactive	25			25			
		$\overline{PRE}$ inactive	20			20			
t_h	Hold time-data after CLK↓		0			0			ns
T_A	Operating free-air temperature		−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†			SN54LS114A			SN74LS114A			UNIT
					MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}		V_{CC} = MIN,	I_I = −18 mA				−1.5			−1.5	V
V_{OH}		V_{CC} = MIN, I_{OH} = −0.4 mA	V_{IH} = 2 V,	V_{IL} = MAX,	2.5	3.4		2.7	3.4		V
V_{OL}		V_{CC} = MIN, I_{OL} = 4 mA	V_{IL} = MAX,	V_{IH} = 2 V,		0.25	0.4		0.25	0.4	V
		V_{CC} = MIN, I_{OL} = 8 mA	V_{IL} = MAX,	V_{IH} = 2 V,					0.35	0.5	
I_I	J or K	V_{CC} = MAX,	V_I = 7 V				0.1			0.1	mA
	$\overline{CLR}$						0.6			0.6	
	$\overline{PRE}$						0.3			0.3	
	CLK						0.8			0.8	
I_{IH}	J or K	V_{CC} = MAX,	V_I = 2.7 V				20			20	μA
	$\overline{CLR}$						120			120	
	$\overline{PRE}$						60			60	
	CLK						160			160	
I_{IL}	J or K	V_{CC} = MAX,	V_I = 0.4 V				−0.4			−0.4	mA
	$\overline{CLR}$						−1.6			−1.6	
	$\overline{PRE}$						−0.8			−0.8	
	CLK						−1.6			−1.6	
I_{OS}§		V_{CC} = MAX,	See Note 2		−20		−100	−20		−100	mA
I_{CC} (Total)		V_{CC} = MAX,	See Note 3			4	6		4	6	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

NOTES: 2. For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V_O = 2.25 V and 2.125 V for the '54 family and the '74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.
3. With all outputs open, I_{CC} is measured with the Q and $\overline{Q}$ outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f_{max}			R_L = 2 kΩ, C_L = 15 pF	30	45		MHz
t_{PLH}	$\overline{CLR}$, $\overline{PRE}$ or CLK	Q or $\overline{Q}$			15	20	ns
t_{PHL}					15	20	ns

NOTE 4: Load circuit and voltage waveforms are shown in Section 1.

recommended operating conditions

			SN54S114			SN74S114A			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.8			0.8	V
I_{OH}	High-level output current				−1			−1	mA
I_{OL}	Low-level output current				20			20	mA
t_w	Pulse duration	CLK	6			6			ns
		CLK low	6.5			6.5			
		$\overline{PRE}$ or $\overline{CLR}$ low	8			8			
t_{su}	Setup time	Data high or low	7			7			ns
t_h	Hold time-data after CLK↓		0			0			ns
T_A	Operating free-air temperature		−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†			SN54S114			SN74S114A			UNIT
					MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}		V_{CC} = MIN,	I_I = −18 mA				−1.2			−1.2	V
V_{OH}		V_{CC} = MIN, I_{OH} = −1 mA	V_{IH} = 2 V,	V_{IL} = 0.8 V,	2.5	3.4		2.7	3.4		V
V_{OL}		V_{CC} = MIN, I_{OL} = 20 mA	V_{IH} = 2 V,	V_{IL} = 0.8 V,			0.5			0.5	V
I_I		V_{CC} = MAX,	V_I = 5.5 V				1			1	mA
I_{IH}	J or K	V_{CC} = MAX,	V_I = 2.7 V				50			50	μA
	$\overline{CLR}$						200			200	
	$\overline{PRE}$						100			100	
	CLK						200			200	
I_{IL}	J or K	V_{CC} = MAX,	V_I = 0.5 V				−1.6			−1.6	mA
	$\overline{CLR}$						−14			−14	
	$\overline{PRE}$						−7			−7	
	CLK						−8			−8	
I_{OS}§		V_{CC} = MAX			−40		−100	−40		−100	mA
I_{CC}#		V_{CC} = MAX,	See Note 3			15	25		15	25	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.
# Values are average per flip-flop.
NOTE 3: With all outputs open, I_{CC} is measured with the Q and $\overline{Q}$ outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f_{max}			R_L = 280 Ω, C_L = 15 pF	80	125		MHz
t_{PLH}	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$			4	7	ns
t_{PHL}	$\overline{PRE}$ or $\overline{CLR}$ (CLK high)	$\overline{Q}$ or Q			5	7	ns
	$\overline{PRE}$ or $\overline{CLR}$ (CLK low)				5	7	
t_{PLH}	CLK	Q or $\overline{Q}$			4	7	ns
t_{PHL}					5	7	ns

NOTE 4: Load circuit and voltage waveforms are shown in Section 1.

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.